



Product Change Notification - LIAL-30ZUQH262

Date:

03 Feb 2020

Product Category:

Memory

Affected CPNs:**Notification subject:**

Memo # ML01202000QB Final Notice: Qualification of 36.3K process technology for selected Microchip products of the AT24C08C and AT24C16C device families.

Notification text:**PCN Status:**

Final notification.

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:

Qualification of 36.3K process technology for selected Microchip products of the AT24C08C and AT24C16C device families.

Pre Change:

Available in 35.8K wafer technology fabricated at Microchip fabrication sites FAB 5 (Colorado Springs, CO, USA) using 6 inch wafers.

Post Change:

Available in 35.8K wafer technology fabricated at Microchip fabrication sites FAB 5 (Colorado Springs, CO, USA) using 6 inch wafers or available at Available in 36.3K wafer technology fabricated at Microchip fabrication sites FAB 5 (Colorado Springs, CO, USA) using 6 inch wafers

Pre and Post Change Summary:

	Pre Change	Post Change	
Wafer Technology	35.8K wafer technology	35.8K wafer technology	36.3K wafer technology
Fabrication Location	FAB 5 (Colorado Springs, CO USA)	FAB 5 (Colorado Springs, CO USA)	FAB 5 (Colorado Springs, CO USA)
Wafer Diameter	6 inches (150 mm)	6 inches (150 mm)	6 inches (150 mm)
Quality certification	ISO/TS16949	ISO/TS16949	ISO9001/TS16949

Impacts to Data Sheet:

None



Change Impact:

None

Reason for Change:

To improve manufacturability by qualifying an additional fabrication site.

Change Implementation Status:

In Progress

Estimated First Ship Date:

April 15, 2020 (date code: 2016)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	February 2020				->	April 2020				
Workweek	06	07	08	09		14	15	16	17	18
Final PCN Issue Date	x									
Qual Report Availability	x									
Estimated Implementation Date								X		

Method to Identify Change:

Traceability code

Qualification Report:

Please open the attachments included with this PCN labeled as PCN_#_Qual Report.

Revision History:

February 03, 2020: Issued final notification. Attached the qualification report. Provided estimated first ship date to be on April 15, 2020

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

[PCN_LIAL-30ZUQH262_QUAL_REPORT.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.



If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

AT24C08C-MAHM-E

AT24C08C-MAHM-T

AT24C08C-PUM

AT24C08C-SSHM-B

AT24C08C-SSHM-T

AT24C08C-STUM-T

AT24C08C-XHM-B

AT24C08C-XHM-T

AT24C16C-MAHM-E

AT24C16C-MAHM-T

AT24C16C-PUM

AT24C16C-SSHM-B

AT24C16C-SSHM-T

AT24C16C-STUM-T

AT24C16C-XHM-B

AT24C16C-XHM-T



MICROCHIP

**QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY**

PCN#: LIAL-30ZUQH262

**Date
December 3, 2019**

**Qualification of 36.3K process technology for selected
Microchip products of the AT24C08C and AT24C16C device
families.**



MICROCHIP

SUMMARY QUALIFICATION REPORT

Purpose: Qualification of 36.3K process technology for selected Microchip products of the AT24C08C and AT24C16C device families.

Document Control #: ML122019000C

Document Revision: A

Device(s): AT24x08/AT24x16/24xx08x/24xx16x

Product: 5V 2W 16K serial EEPROM

Mask Identification #: 363V4

Process 0.25um, 6" wafer

MSL: 3301



MICROCHIP

SUMMARY QUALIFICATION REPORT

Qualification Material:

LOT	LOT 1
DEVICE	24AA16-E/P
MASK, REV	363V4 (A2)
WAFER FAB	Fab 5
WAFER PROCESS	0.25um, 6"
WAFER LOT	MCSO520188047.000
ASSEMBLY LOT	MMT-202100278.000
PACKAGE	8LD PDIP
ASSEMBLY SITE	MMT
FINAL TEST	MTAI
QUAL #	ESD: ML0920190079 LU: ML092019007A CDM: ML102019003B
QUAL TEST	HTOL / ELFR / HTDR / ESD / LU / CDM

Conclusion:

Pass Fail

Based on the results, the 363V4 mask has meet the reliability guidelines implemented in the qualification plan.

Qualification Data:

Early Life Failure Rate (ELFR):

Test Method	AEC Q100-008
Test Condition	125°C / 24 hours
Sample Size (800 ea. min)	(Fail/Pass)
Lot 1	0 / 815

Pre & Post Testing was done @ +25°C, -40°C, +85°C, and 125°C.

High Temperature Operating Life (HTOL)

Test Method	AEC Q100-005
Test Condition	125°C / 408 hours
Sample Size (77 ea. min)	(Fail/Pass)
Lot 1	0 / 615

Pre & Post Testing was done @ +25°C, -40°C, +85°C, and 125°C.

High Temperature Data Retention (HTDR)

Test Method	AEC Q100-005
Test Condition	125°C / 504 hours
Sample Size (231 ea. min)	(Fail/Pass)
Lot 1	0 / 246

Pre & Post Testing was done @ +25°C, -40°C, +85°C, and 125°C.

ESD and Latch Up

Test	Reference Method	Sample	Highest Passing Voltage
ESD – HBM	AEC Q100-002 JS-001-2017	18/Lot 1	+/- 4500V
ESD – CDM	AEC Q100-11 (ANSI/ESD S5.3.1)	18/Lot 1	+/- 2000V on all pins
Latch Up	AEC Q100-004 JEDEC JESD78	6/Lot 1 6/Lot 1 6/Lot 1	6 Pass @ +25°C ^a 6 Pass @ +125°C ^a 6 Pass @ +25°C ^b

All Pre & Post Testing done @ +25°C, +85°C, and 125°C.

^a +/-105mA Pulse / +Overvoltage stress

^b +/-200mA Pulse / +Overvoltage stress

MTBF/FIT Data:

These calculations only consider ELFR and DLT data from this Qualification	
Activation Energy	0.7 eV
Application Temperature	55 degrees C

	Infant Mortality	Total Life	MTBF (Hours)
Device Hours	19,560	270,480	N/A
Fit Rate - 50% Confidence	136	10	101,595,911
Fit Rate - 60% Confidence	180	13	76,854,340
Fit Rate - 90% Confidence	452	33	30,583,417

Note: One FIT is one fail in 10⁹ device hours

	Best Estimated Failure Rate (%KHR)
Infant Mortality	0.0136
Total Life	0.0010